

### Trench IGBT Modules

### SEMiX603GAL12E4p

### **Features**

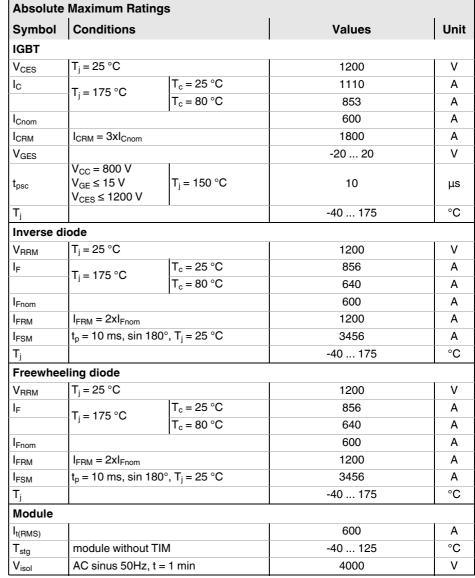
- · Homogeneous Si
- Trench = Trenchgate technology
- V<sub>CE(sat)</sub> with positive temperature coefficient
- High short circuit capability
- Press-fit pins as auxiliary contacts
- Thermally optimized ceramic
- UL recognized, file no. E63532

### Typical Applications\*

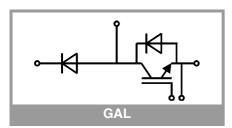
- · AC inverter drives
- UPS
- Renewable energy systems

#### Remarks

- Product reliability results are valid for  $T_{i=150}^{\circ}$ C
- V<sub>isol</sub> between temperature sensor and power section is only 2500V
- For storage and case temperature with TIM see document "TP(\*) SEMiX 3p"



Characteristics							
Symbol	Conditions		min.	typ.	max.	Unit	
IGBT						•	
· CE(Sat)	$I_C = 600 \text{ A}$ $V_{GE} = 15 \text{ V}$ chiplevel	T <sub>j</sub> = 25 °C		1.80	2.05	V	
		T <sub>j</sub> = 150 °C		2.03	2.30	V	
$V_{CE0}$	chiplevel	T <sub>j</sub> = 25 °C		0.87	1.01	V	
	Criipievei	T <sub>j</sub> = 150 °C		0.77	0.9	V	
<u>~-</u>	V <sub>GE</sub> = 15 V	T <sub>j</sub> = 25 °C		1.55	1.73	mΩ	
	chiplevel	T <sub>j</sub> = 150 °C		2.1	2.3	mΩ	
$V_{GE(th)}$	V <sub>GE</sub> =V <sub>CE</sub> , I <sub>C</sub> = 22.2 mA		5.3	5.8	6.3	V	
I <sub>CES</sub>	V <sub>GE</sub> = 0 V, V <sub>CE</sub> = 1200 V, T <sub>j</sub> = 25 °C				5	mA	
C <sub>ies</sub>	V <sub>CE</sub> = 25 V V <sub>GE</sub> = 0 V	f = 1 MHz		37.5		nF	
Coes		f = 1 MHz		2.31		nF	
C <sub>res</sub>		f = 1 MHz		2.04		nF	
$Q_{G}$	V <sub>GE</sub> = - 8 V+ 15 V			3450		nC	
R <sub>Gint</sub>	T <sub>j</sub> = 25 °C			1.2		Ω	





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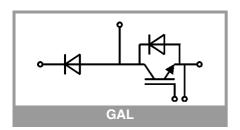
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Characte	eristics					
Symbol	Conditions		min.	typ.	max.	Unit
IGBT						
t <sub>d(on)</sub>	V <sub>CC</sub> = 600 V	T <sub>j</sub> = 150 °C		160		ns
t <sub>r</sub>	$\begin{aligned} &I_{C} = 600 \text{ A} \\ &V_{GE} = +15/-15 \text{ V} \\ &R_{G \text{ on}} = 1.5 \Omega \\ &R_{G \text{ off}} = 1.5 \Omega \\ &\text{di/dt}_{on} = 7270 \text{ A/}\mu\text{s} \end{aligned}$	T <sub>j</sub> = 150 °C		80		ns
E <sub>on</sub>		T <sub>j</sub> = 150 °C		59		mJ
t <sub>d(off)</sub>		T <sub>j</sub> = 150 °C		540		ns
t <sub>f</sub>		T <sub>j</sub> = 150 °C		130		ns
E <sub>off</sub>	$\begin{array}{l} \text{di/dt}_{\text{off}} = 4270 \text{ A/}\mu\text{s} \\ \text{du/dt} = 3500 \text{ V/}\mu\text{s} \\ \text{L}_{\text{s}} = 21 \text{ nH} \end{array}$	T <sub>j</sub> = 150 °C		76		mJ
R <sub>th(j-c)</sub>	per IGBT				0.037	K/W
R <sub>th(c-s)</sub>	per IGBT (λ <sub>grease</sub> =0	.81 W/(m*K))		0.035		K/W
R <sub>th(c-s)</sub>	per IGBT, pre-applied phase change material			0.025		K/W
Inverse d	iode					
$V_F = V_{EC} \\$	$I_F = 600 \text{ A}$	T <sub>j</sub> = 25 °C		2.08	2.44	V
	V <sub>GE</sub> = 0 V chiplevel	T <sub>j</sub> = 150 °C		2.08	2.34	V
$V_{F0}$	chiplevel	T <sub>j</sub> = 25 °C		1.39	1.59	V
		T <sub>j</sub> = 150 °C		1.08	1.18	V
r <sub>F</sub>	chiplevel	T <sub>j</sub> = 25 °C		1.16	1.42	mΩ
		T <sub>j</sub> = 150 °C		1.67	1.93	mΩ
I <sub>RRM</sub>	I <sub>F</sub> = 600 A	T <sub>j</sub> = 150 °C		480		Α
Q <sub>rr</sub>	di/dt <sub>off</sub> = 6880 A/μs - V <sub>GE</sub> = -15 V	T <sub>j</sub> = 150 °C		90		μC
E <sub>rr</sub>	$V_{CC} = 600 \text{ V}$	T <sub>j</sub> = 150 °C		33		mJ
R <sub>th(j-c)</sub>	per diode				0.065	K/W
R <sub>th(c-s)</sub>	per diode (λ <sub>grease</sub> =0	.81 W/(m*K))		0.039		K/W
R <sub>th(c-s)</sub>	per diode, pre-applied phase change material			0.031		K/W
Freewhee	eling diode					
$V_F = V_{EC}$	I <sub>F</sub> = 600 A	T <sub>j</sub> = 25 °C		2.08	2.44	V
	V <sub>GE</sub> = 0 V chiplevel	T <sub>j</sub> = 150 °C		2.08	2.34	V
V <sub>F0</sub>	chiplevel	T <sub>j</sub> = 25 °C		1.39	1.59	V
		T <sub>j</sub> = 150 °C		1.08	1.18	V
r <sub>F</sub>	chiplevel	T <sub>j</sub> = 25 °C		1.16	1.42	mΩ
		T <sub>j</sub> = 150 °C		1.67	1.93	mΩ
I <sub>RRM</sub>	I <sub>F</sub> = 600 A	T <sub>j</sub> = 150 °C		480		Α
Q <sub>rr</sub>	di/dt <sub>off</sub> = 6880 A/μs	T <sub>j</sub> = 150 °C		90		μС
Err	$V_{GE} = -15 \text{ V}$ $V_{CC} = 600 \text{ V}$	T <sub>j</sub> = 150 °C		33		mJ
R <sub>th(j-c)</sub>	per diode				0.065	K/W
R <sub>th(c-s)</sub>	per diode (λ <sub>grease</sub> =0.81 W/(m*K))			0.039		K/W
R <sub>th(c-s)</sub>	per diode, pre-applied phase change material			0.031		K/W





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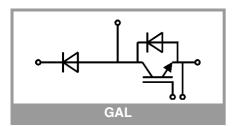
### Typical Applications\*

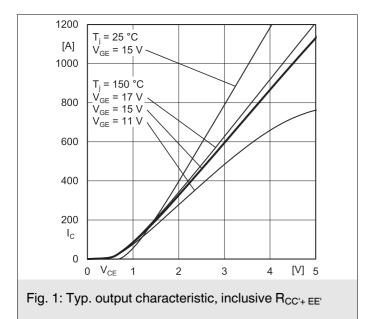
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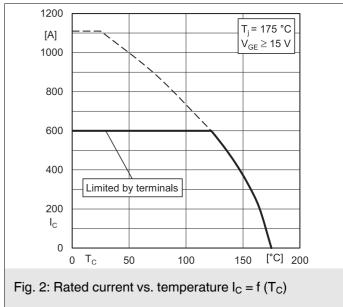
### Remarks

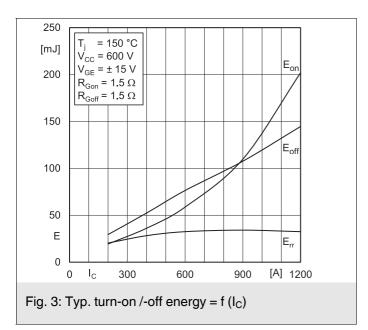
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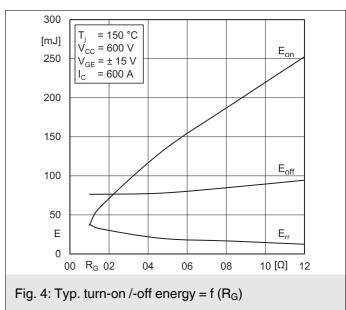
Characteristics							
Symbol	Conditions		min.	typ.	max.	Unit	
Module							
L <sub>CE</sub>				20		nΗ	
R <sub>CC'+EE'</sub>	measured per	T <sub>C</sub> = 25 °C	1.2		mΩ		
	switch	T <sub>C</sub> = 125 °C	1.65		mΩ		
Rth <sub>(c-s)1</sub>	calculated without thermal coupling		0.009			K/W	
Rth <sub>(c-s)2</sub>	including thermal coupling, Ts underneath module ( $\lambda_{grease}$ =0.81 W/(m*K))		0.014			K/W	
Rth <sub>(c-s)2</sub>	including thermal coupling, Ts underneath module, pre-applied phase change material			0.011		K/W	
Ms	to heat sink (M5)		3		6	Nm	
$M_t$		to terminals (M6)	3		6	Nm	
						Nm	
W					350	g	
Temperature Sensor							
R <sub>100</sub>	T <sub>c</sub> =100°C (R <sub>25</sub> =5 kΩ)		493 ± 5%			Ω	
B <sub>100/125</sub>	R <sub>(T)</sub> =R <sub>100</sub> exp[B <sub>100/125</sub> (1/T-1/T <sub>100</sub> )]; T[K];		3550 ±2%			K	

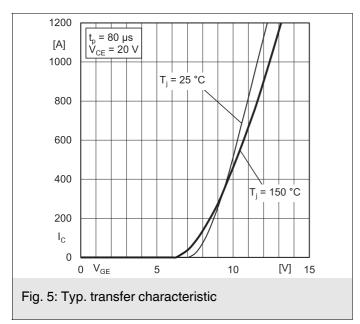


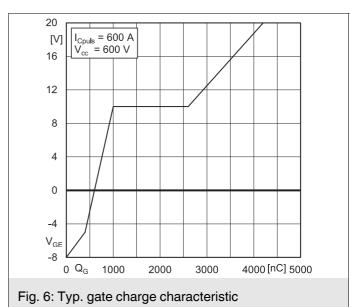


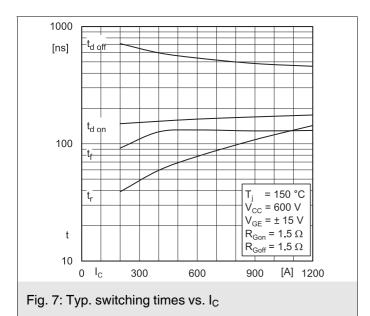


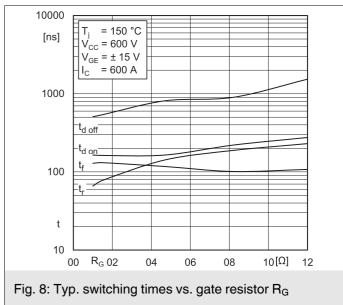


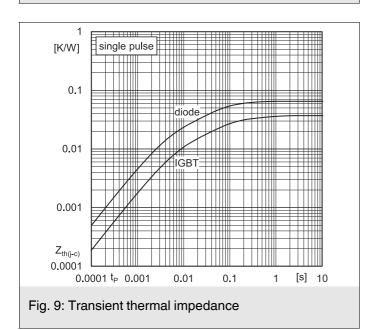


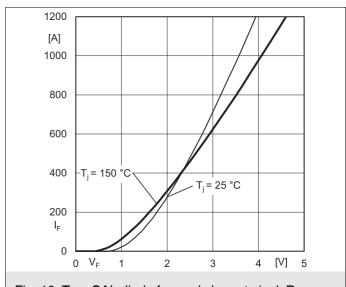












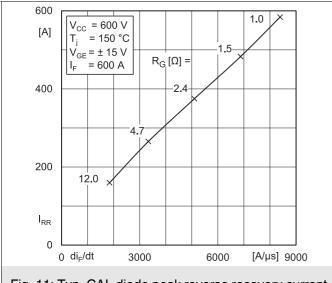


Fig. 10: Typ. CAL diode forward charact., incl. R<sub>CC'+ EE'</sub>

1200

900

600-400 I<sub>F</sub> [A] =

[A/µs]10000

200

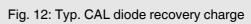
1.0

1.5

2.4

 $R_G[\Omega] =$ 

5000



12.0 4.7

Fig. 11: Typ. CAL diode peak reverse recovery current

150

[µC]

100

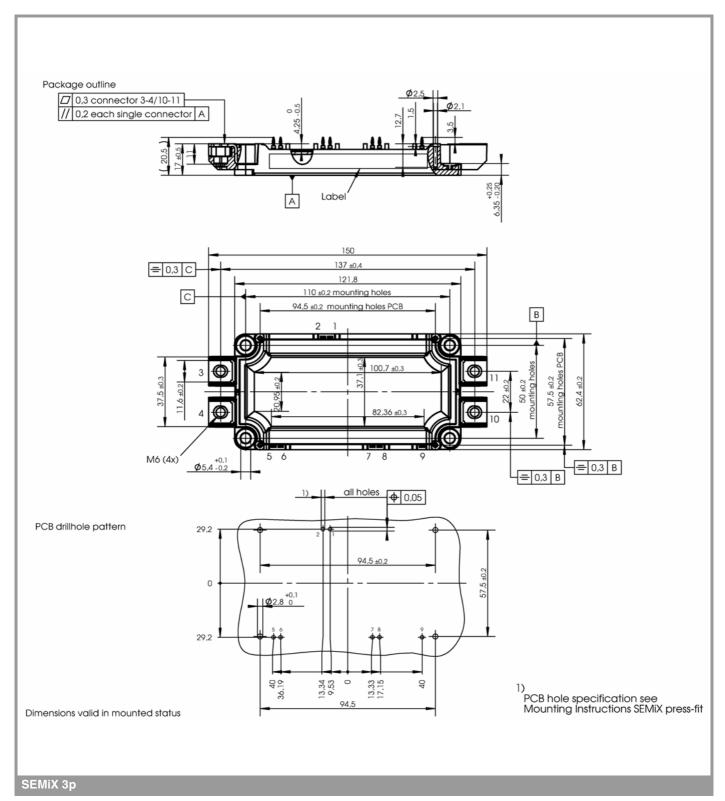
50

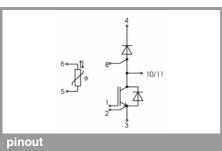
 $Q_{rr}$ 

0 di<sub>F</sub>/dt

 $V_{CC} = 600 \overline{V}$ 

 $T_j = 150 \,^{\circ}\text{C}$  $V_{GE} = \pm 15 \,^{\circ}\text{V}$ 





This is an electrostatic discharge sensitive device (ESDS), international standard IEC 60747-1, chapter IX.

#### \*IMPORTANT INFORMATION AND WARNINGS

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